

	<b>Hit s</b>	<b>Search Text</b>	<b>DBs</b>
17	40	((expos\$4 or irradiat\$4 or illuminat\$4) same ((reflect\$4 or EUV) near20 (reticle or photomask or mask)) same (pluralit\$4 or multiple)) and (pattern\$4 same (mask or reticle or photomask) same ((horizontal\$3 near26 vertical\$3) or (X\$3direction near17 Y\$3direction near19 Z\$3direction) or (parallel near18 perpendicular or orthogonal\$3))) and ((wafer or substrate or object) same (stag\$4 or hold\$4) same (driv\$4 or mov\$5 or rotat\$4)) and ((mask or reticle or photomask) same (stag\$4 or hold\$4 or position\$4) same (driv\$4 or mov\$5 or rotat\$4) same (adjust\$4 or chang\$4) same (angle or tilt or deviation))	US - PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	<b>Hit s</b>	<b>Search Text</b>	<b>DBs</b>
18	40	((expos\$4 or irradiat\$4 or illuminat\$4) same ((reflect\$4 or EUV) near20 (reticle or photomask or mask)) same (pluralit\$4 or multiple)) and (pattern\$4 same (mask or reticle or photomask) same ((horizontal\$3 near26 vertical\$3) or (X\$3direction near17 Y\$3direction near19 Z\$3direction) or (parallel near18 perpendicular or orthogonal\$3))) and ((wafer or substrate or object) same (stag\$4 or hold\$4) same (driv\$4 or mov\$5 or rotat\$4)) and ((mask or reticle or photomask) same (stag\$4 or hold\$4 or position\$4) same (driv\$4 or mov\$5 or rotat\$4) same (adjust\$4 or chang\$4 or (yaw\$4 near6 error)) same (angle or tilt or deviation))	US - PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Hit s	Search Text	DBs
19	36	((expos\$4 or irradiat\$4 or illuminat\$4) same ((reflect\$4 or EUV) near20 (reticle or photomask or mask)) same (pluralit\$4 or multiple)) and (pattern\$4 same (mask or reticle or photomask) same ((horizontal\$3 near26 vertical\$3) or (X\$3direction near17 Y\$3direction near19 Z\$3direction) or (parallel near18 (perpendicular or orthogonal\$3)))) and ((wafer or substrate or object) same (stag\$4 or hold\$4) same (driv\$4 or mov\$5 or rotat\$4)) and ((mask or reticle or photomask) same (stag\$4 or hold\$4 or position\$4) same (driv\$4 or mov\$5 or rotat\$4) same (adjust\$4 or chang\$4 or (yaw\$4 near6 error)) same (angle or tilt or deviation)) and (EUV or UV or X\$3ray or excimer)	US - PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB